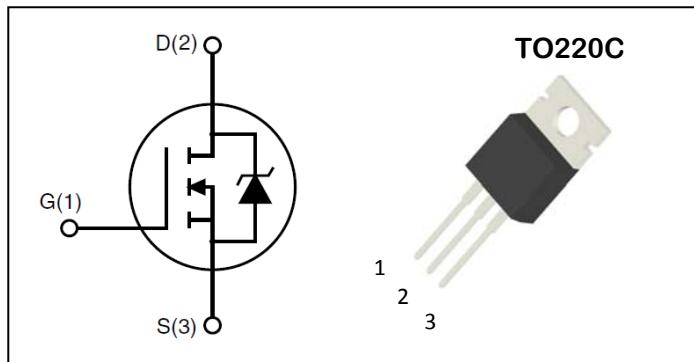


**N-Channel Enhancement Mode Field Effect Transistor****PRODUCT SUMMARY**

$V_{DSS}$	$I_D$	$R_{DS(ON)}$ ( $m\Omega$ )
100V	57A	17m $\Omega$

**Features:**

- Low Gate Charge for Fast Switching Application
- Low  $R_{DS(ON)}$  to Minimize Conductive Loss
- 100% EAS Guaranteed
- Optimized  $V_{(BR)DSS}$  Ruggedness
- Lead-Free, RoHS Compliant

**Description:**

The ADM57N10 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

**Absolute Maximum Ratings (  $T_A = 25^\circ C$  unless otherwise specified )**

Symbol	Parameter	Ratings	Unit
<b>Common Ratings</b>			
$V_{DSS}$	Drain-Source Voltage	100	V
$V_{GSS}$	Gate-Source Voltage	$\pm 20$	
$T_J$	Maximum Junction Temperature	175	°C
$T_{STG}$	Storage Temperature Range	-55 to 175	°C
$I_S$	Diode Continuous Forward Current	57	A
<b>Mounted on Large Heat Sink</b>			
$I_{DM}$	300 $\mu s$ Pulse Drain Current Tested <sup>(2)</sup>	$T_C=25^\circ C$	160
$I_D$	Continuous Drain Current <sup>(1)</sup>	$T_C=25^\circ C$	57
		$T_C=100^\circ C$	40
$P_D$	Maximum Power Dissipation	$T_C=25^\circ C$	160

**Thermal Characteristics**

Symbol	Parameter	Ratings	Unit
$R_{thJC}$	Thermal resistance junction-case max <sup>(1)</sup>	0.94	°C/W
$R_{thJA}$	Thermal resistance junction-ambient max <sup>(1)</sup>	62	°C/W

**Electrical Characteristics** (TA=25°C Unless Otherwise Noted)

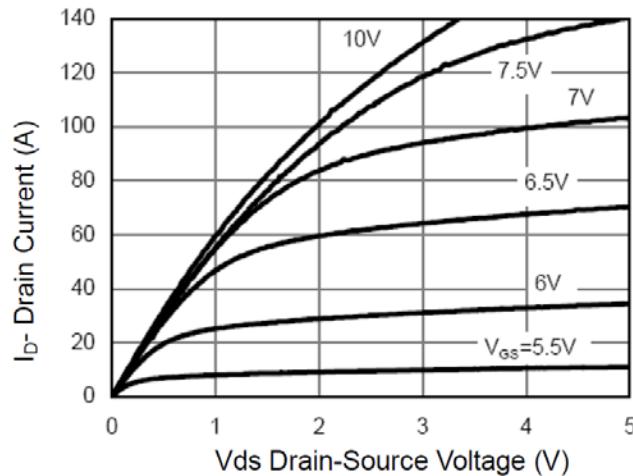
Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
<b>On/off Characteristics</b>						
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>DS</sub> =250uA	100	110	--	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =100V, V <sub>GS</sub> =0V , T <sub>J</sub> =25°C	--	--	1	uA
V <sub>Gs(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>DS</sub> =250uA	2	3	4	V
I <sub>GSS</sub>	Gate Leakage Current	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	--	--	±100	nA
R <sub>Ds(ON)</sub>	Drain-SourceOn-stateResistance <sup>(2)</sup>	V <sub>GS</sub> = 10V, I <sub>DS</sub> =28A	--	14	17	mΩ
<b>Dynamic Characteristics</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =25V, Frequency=1MHz	--	3400	--	pF
C <sub>oss</sub>	Output Capacitance		--	260	--	
C <sub>rss</sub>	Reverse Transfer Capacitance		--	210	--	
<b>Switching Characteristics</b>						
t <sub>d(ON)</sub>	Turn-on Delay Time	V <sub>DS</sub> =30V, I <sub>D</sub> = 2A, V <sub>GS</sub> = 10V, R <sub>GEN</sub> =2.5 Ω	--	15	--	nS
t <sub>r</sub>	Turn-on Rise Time		--	11	--	
t <sub>d(OFF)</sub>	Turn-off Delay Time		--	52	--	
t <sub>f</sub>	Turn-off Fall Time		--	13	--	
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =30V, V <sub>GS</sub> = 10V, I <sub>DS</sub> =30A	--	94	--	nC
Q <sub>gs</sub>	Gate-Source Charge		--	16	--	
Q <sub>gd</sub>	Gate-Drain Charge		--	24	--	
<b>Avalanche Characteristics</b>						
EAS	Single Pulse Avalanche Energy <sup>(3)</sup>	V <sub>DD</sub> =30V,L=0.5mH ,V <sub>GS</sub> =10V,R <sub>g</sub> =25 Ω	580	--	--	mJ
<b>Diode Characteristics</b>						
V <sub>SD</sub>	Diode Forward Voltage <sup>(2)</sup>	I <sub>SD</sub> = 28A, V <sub>GS</sub> = 0	--	0.85	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>SD</sub> =28A, dI <sub>SD</sub> /dt=100A/μs	--	33	--	ns
q <sub>rr</sub>	Reverse Recovery Charge		--	54	--	nC

## NOTES:

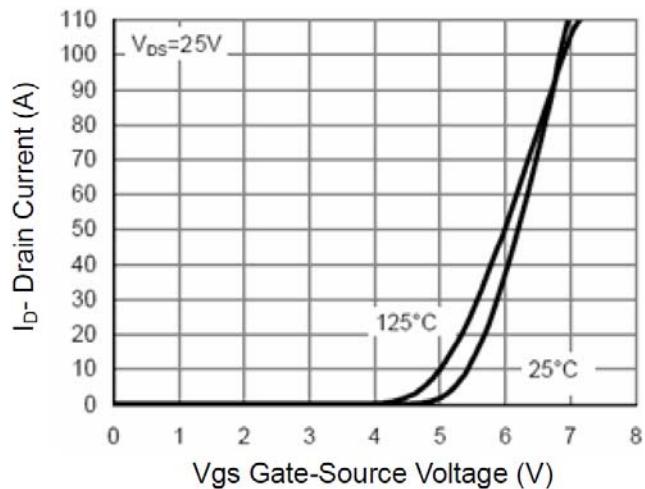
1. Surface Mounted on FR4 Board, t ≤ 10 sec.
- 2.The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3.The Min. value is 100% EAS tested guarantee.

## Typical Performance Characteristics

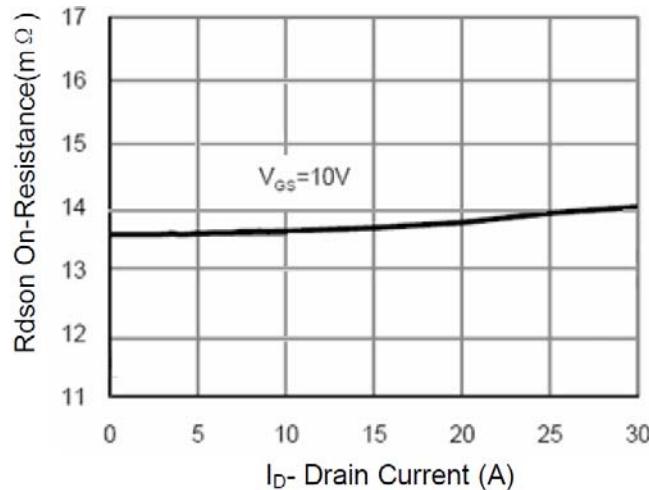
**Figure 1: On-Region Characteristics**



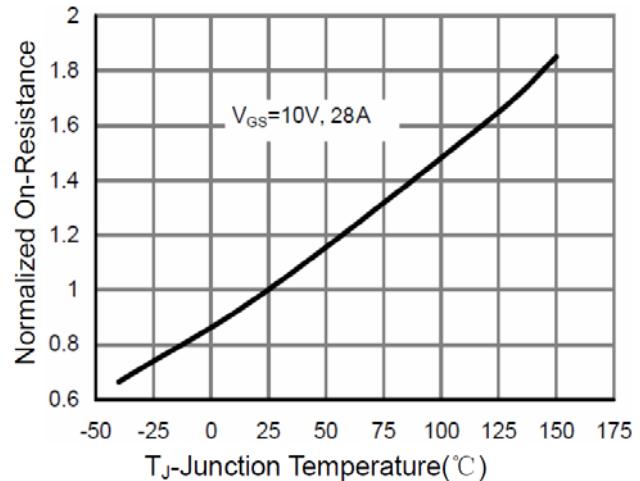
**Figure 2: Transfer Characteristics**



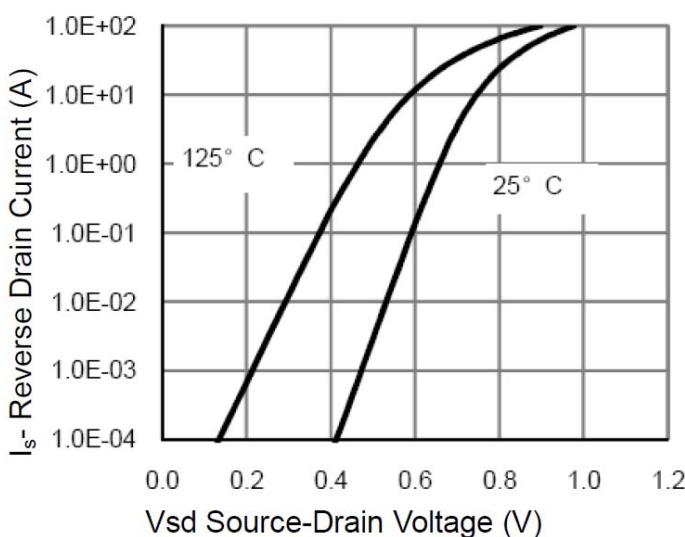
**Figure 3:  $R_{DSon}$ - Drain Current**



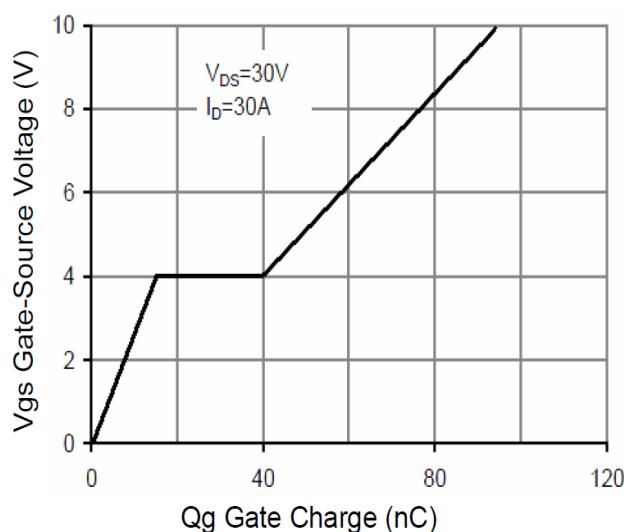
**Figure 4:  $R_{DSon}$ -Junction Temperature**

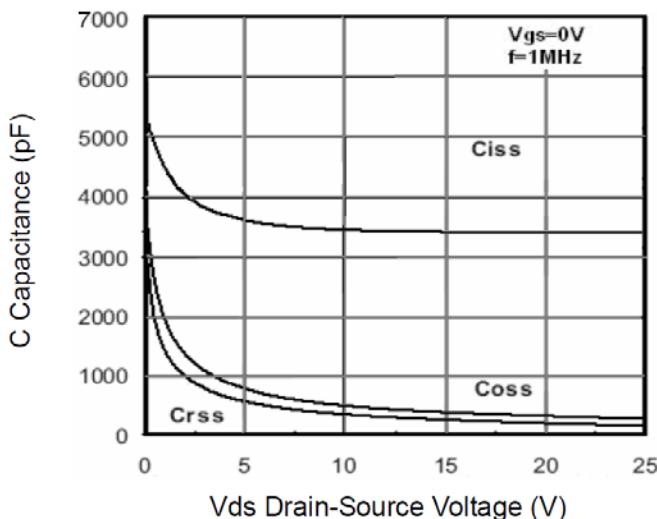
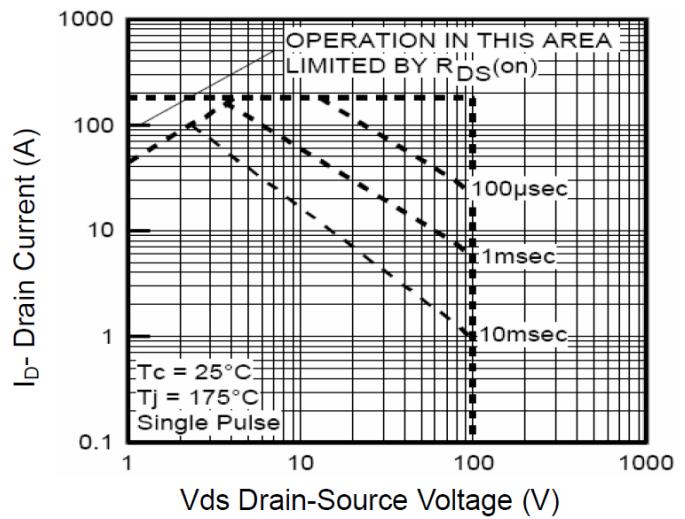
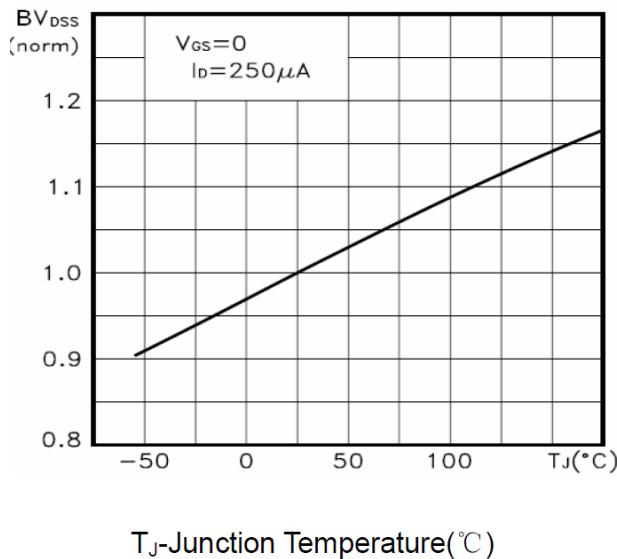
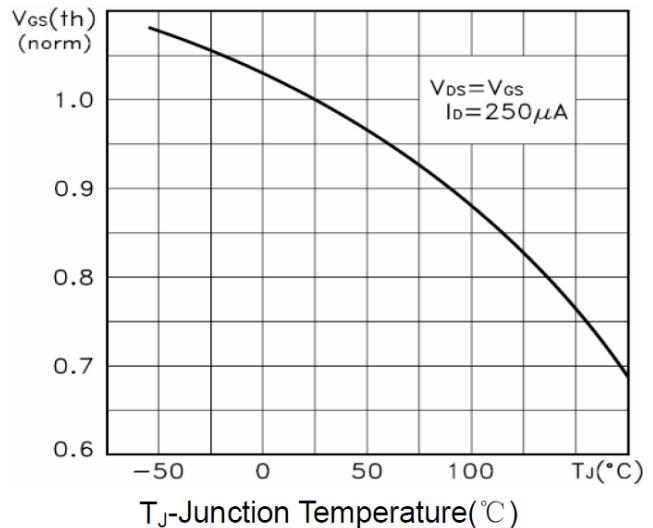
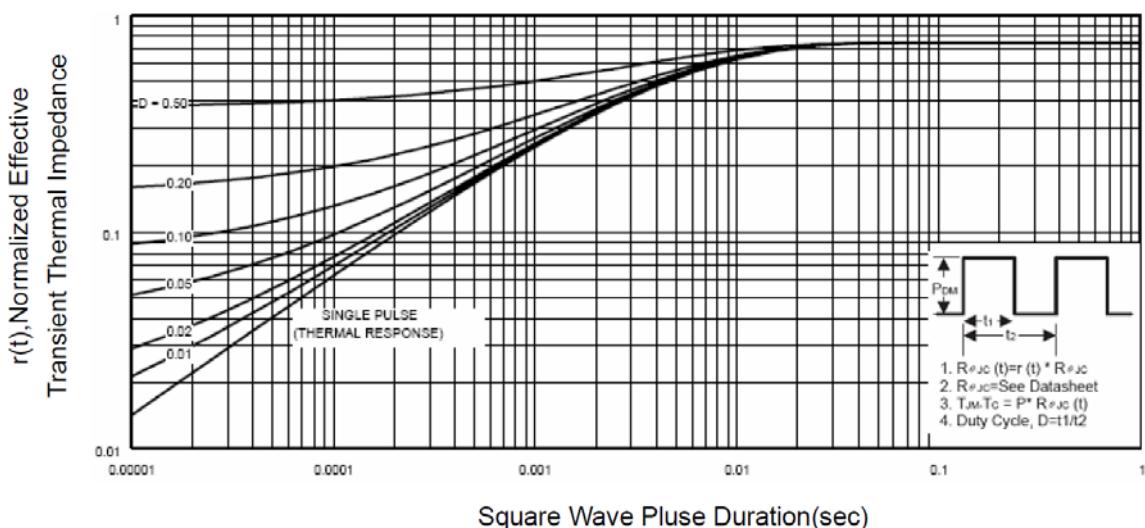


**Figure 5: Source- Drain Diode Forward**



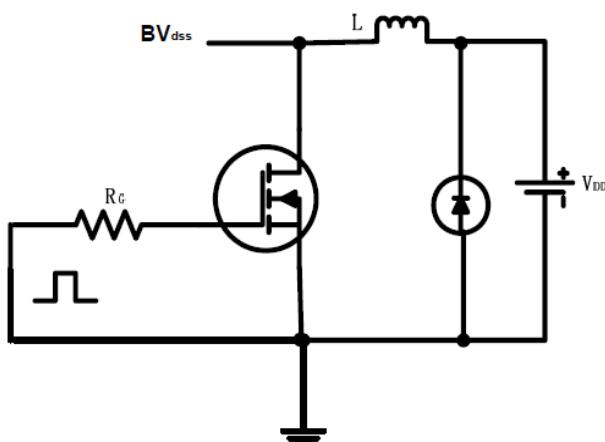
**Figure 6: Gate Charge Characteristics**



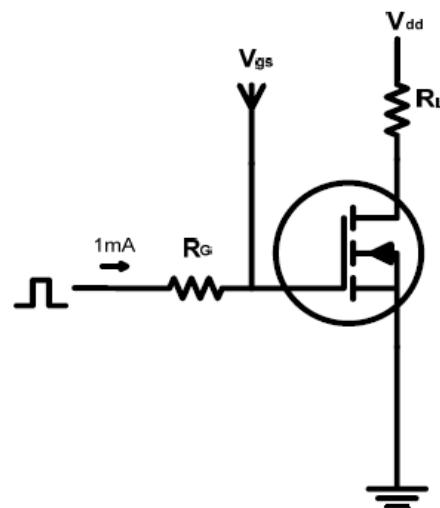
**Figure 7: Capacitance vs Vds****Figure 8: Safe Operation Area****Figure 9:  $\text{BV}_{DSS}$  vs Junction Temperature****Figure 10:  $V_{GS(\text{th})}$  vs Junction Temperature****Figure 11: Normalized Maximum Transient Thermal Impedance**

## Test circuits and Waveforms

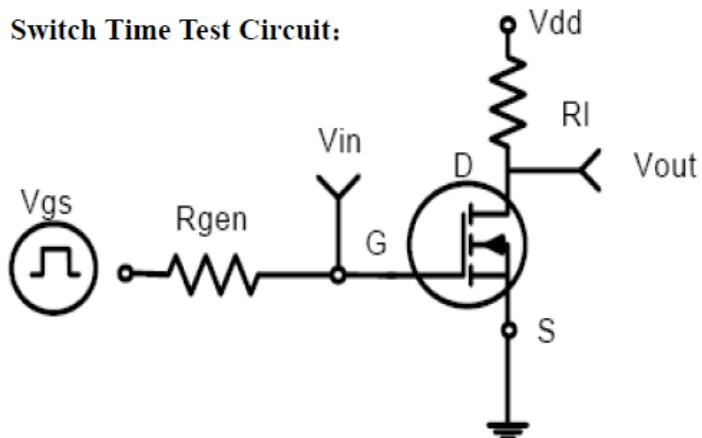
EAS test circuits:



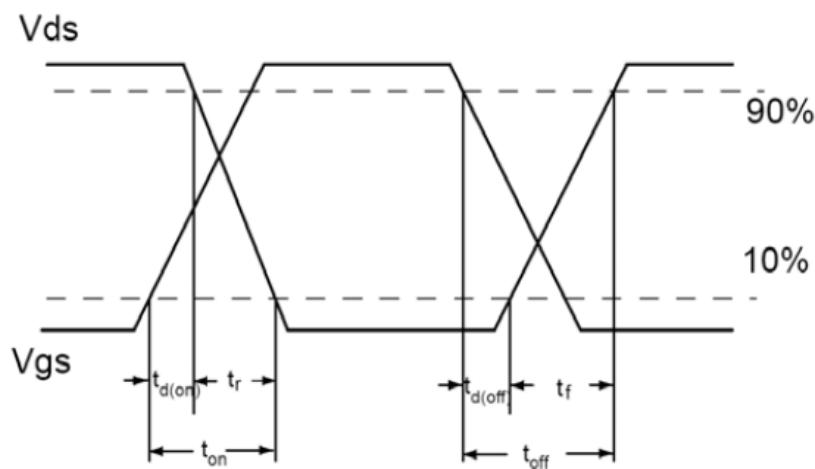
Gate charge test circuit:



Switch Time Test Circuit:

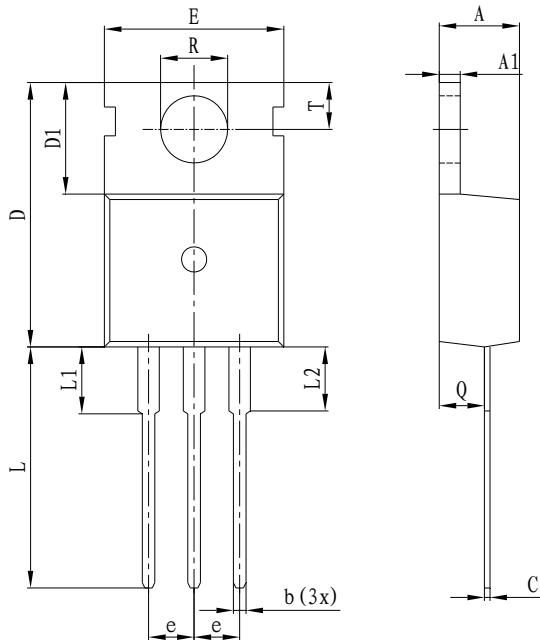


Switch Waveforms:



## PACKAGE MECHANICAL DATA

## TO-220C Package Dimension



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
e	2.54 TYP		0.099TYP	
A	4.10	4.70	0.161	0.185
A1	1.25	1.40	0.049	0.055
b	0.60	0.90	0.023	0.035
C	0.40	0.70	0.016	0.027
D	15.20	16.00	0.598	0.630
D1	5.90	6.60	0.232	0.259
E	9.70	10.30	0.382	0.405
L	12.80	15.00	0.504	0.590
L1	2.79	3.30	0.110	0.130
R	3.50	3.80	0.138	0.149
T	2.70	3.00	0.106	0.118
Q	2.20	2.60	0.086	0.102
L2		3.00		0.118

## Ordering information

Part number	Package	Marking	Packing	Quantity
ADM57N10	TO-220C	ADM57N10	Tube	50pcs